

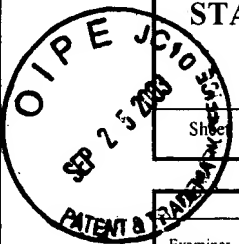
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PTO/SB/08A (08-00)

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	
				09/894,125	
				Filing Date	
				June 29, 2001	
				First Named Inventor	
		Shunpei YAMAZAKI et al.			
Group Art Unit		2823			
Examiner Name		B. Kebede			
Attorney Docket Number		0756-2330			
Sheet	1	of	1		

FOREIGN PATENT DOCUMENTS								
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Office ³	Number ⁴	Kind Code ⁵ (if known)				
		JP	07-130652			05/19/1995		AB

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		R. Shimokawa et al., <i>Characterization of High-Efficiency Cast-Si Solar Cell Wafers by MBIC Measurement</i> , Japanese Journal of Applied Physics, Volume 27, No. 5, May, 1988, pp. 751-758	
		H. Furue et al., <i>P-78: Characteristics and Driving Scheme of Polymer-Stabilized Monostable FLC/D Exhibiting Fast Response Time and High Contrast Ratio with Gray-Scale Capability</i> , SID, 1998	
		T. Yoshida, 33.2: <i>A Full-Color Thresholdless Antiferroelectric LCD Exhibiting Wide Viewing Angle with Fast Response Time</i> , SID Digest, 1997, pp. 841-844.	
		H. Dorin, et al., <i>Chemistry the Study of Matter</i> , Prentice Hall, Fourth Edition, 1992, p. 532.	
		Y. Aya, et al., <i>Improvement of SPC Poly-Si Film Using the ELA Method</i> , 1997 International Workshop on Active-Matrix Liquid-Crystal Displays, September 11-12, 1997, pp. 167-170.	
		H. Abe, et al., <i>High-Performance Poly-Crystalline Silicon TFTs Fabricated Using the SPC and ELA Methods</i> , 1998 International Workshop on Active-Matrix Liquid-Crystal Displays, July 9-10, 1998, pp. 85-88.	
		S. Inui, et al., <i>Thresholdless Antiferroelectricity in Liquid Crystals and its Application Displays</i> , J. Mater. Chem., 1996, pp. 671-673	

Examiner Signature	Date Considered
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